SUISSE TECHNOLOGY PARTNERS

Reference Material Certificate

116/05

Aluminium Base (Type of Standard)
Al pure (99.99 – 99.95% Al), Set 110

Certified Values

Element	Analytical methods used for certification	Mass fraction [1] in [%]	Uncertainty [2] in mass fraction [%]
Silicon (Si)	a, g, h	0.0112	0.0006
Iron (Fe)	b, c, e, g	0.0114	0.0003
Copper (Cu)	a, b, d, e	0.0074	0.0002
Manganese (Mn)	a, b, c, d, e	0.0048	0.0002
Magnesium (Mg)	a, b, c, d, e	0.0052	0.0002
Chromium (Cr)	a, b, c, d, e	0.0054	0.0002
Nickel (Ni)	a, b, c, e	0.0048	0.0002
Zinc (Zn)	a, b, d, e	0.0048	0.0002
Titanium (Ti)	a, b, c, d	0.0019	0.0002
Silver (Ag)	b, d	0.0020	0.0002
Arsenic (As)	c, e	0.0042	0.0004
Boron (B)	b, d	0.0004	0.0002
Barium (Ba)	b, c, d, e	< 0.0001	-
Beryllium (Be)	b, c, d, e	0.00027	0.00001
Bismuth (Bi)	b, c, e	0.0019	0.0002
Calcium (Ca)	b, c	0.0009	0.0002
Cadmium (Cd)	a, b, c, d, e	0.0010	0.0001
Cerium (Ce)	b, c, d, e	0.0015	0.0004
Cobalt (Co)	a, b, c, d, e	0.0020	0.0001
Gallium (Ga)	a, b, c, d, e	0.0049	0.0002
Mercury (Hg)	e, g, k	0.0014	0.0004
Indium (In)	b, c, g	0.0050	0.0003
Lanthanum (La)	b, c, d, e	0.0035	0.0003
Lithium (Li)	a, b, c, d, e	0.00025	0.00002
Molybdenum (Mo)	b, d, e	0.0077	0.0004
Sodium (Na)	b, g	< 0.0001	-
Phosphorous (P)	c, e	0.0013	0.0002
Lead (Pb)	b, c, d	0.0030	0.0002
Antimony (Sb)	c, e	0.0042	0.0007
Scandium (Sc)	a, b, c, e	0.0018	0.0001

Element	Analytical methods used for certification	Mass fraction [1] in [%]	Uncertainty [2] in mass fraction [%]
Tin (Sn)	a, b, d, e	0.0029	0.0001
Strontium (Sr)	b, c, d, e	0.00079	0.00006
Tantalum (Ta)	b, c, d	0.0016	0.0002
Thallium (Tl)	b, c, d	0.0027	0.0002
Vanadium (V)	a, b, c, d, e	0.0026	0.0001
Tungsten (W)	b, c, d, e	0.0020	0.0002
Zirconium (Zr)	a, c, e	0.0019	0.0001

[1] Unweighted mean value of the means of accepted sets of data (consisting of at least 5 but usually 6 single results), each set being obtained by a different digestion and / or method of measurement.

[2] Uncertainty generated from the 95% confidence interval (calculated as $C(95\%) = t \times S_M / \sqrt{n}$ where t is the appropriate two sided Student's t value at the 95% confidence level for n acceptable mean values and S_M is the single standard deviation of the accepted mean values) in combination with the standard deviation from sample homogeneity measurements using the square root of the summed squares.

Analytical methods used for certification

a	ICP-OES, digestion with caustic soda
b	ICP-OES, digestion with acid
c	ICP-OES, closed vessel digestion with acid
d	ICP-MS, digestion with acid
e	ICP-MS, closed vessel digestion with acid
f	FAAS, digestion with acid
g	Spark OES, solid sample analysis
h	Spectrophotometry, digestion with caustic soda
i	Spectrophotometry, digestion with acid
k	CV-AAS, closed vessel digestion with acid

Abbreviations

ICP-OES	Inductively coupled plasma - optical emission spectrometry
ICP-MS	Inductively coupled plasma - mass spectrometry
FAAS	Flame atomic absorption spectrometry
CV-AAS	Cold vapor atomic absorption spectrometry
Spark OES	Spark optical emission spectrometry

Manufacturing
This certified reference material is produced using six strand vertical continuous casting out of a single melt.

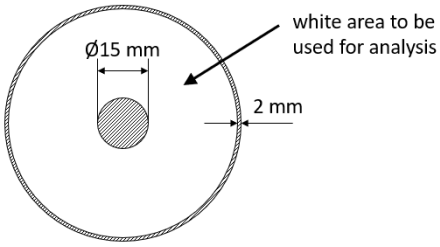
Analysis
The analysis of this material was performed in our ISO/IEC 17025 accredited analytical laboratory (STS 0023) by different established analytical procedures. Every certified value is the result of multiple independent analyses.

Homogeneity
Homogeneity testing is performed by means of spark optical emission spectroscopy. Tests involve making multiple measurements on individual samples taken at regular intervals along the entire length of each cast rod. Depending on the mass content of the element, the relative standard deviation of multiple measurements between discs or within one disc is typically found between 0.3% - 3% for alloying and other elements (Si, Fe, Cu, Mn, Mg, Cr, Ni, Zn, Ag, Be, Cd, Ga, Mo, Pb, Sc, Sn, Tl, V and Zr) and 4% - 15% for some trace elements (As, B, Bi, Ca, Ce, Co, In, La, Li, P, Sb, Sr, Ta, Ti and W). The homogeneity within one sample and between discs (cast homogeneity) is taken into account in the calculation of the uncertainty of the certified value.

Description of Sample
This reference material is available in the form of discs (approx. 60mm diameter and 25mm height).

Intended use and Stability
This certified reference material is primarily intended for use in spark optical emission spectroscopy. Other applications are X-ray fluorescence spectrometry (XRF) and classical wet chemical procedures. It may be used for instrument calibration, validation of analytical methods and drift correction over time. The material will remain stable for the period given below (certificate validity) if it is stored in a dry (non-condensing) and clean environment at room temperature (≤40 °C).

Instructions for Use
Measurements should be made within a ring (see white area in the picture). For wet chemical analysis chips have to be prepared by turning or milling of the sample surface. The minimum mass to be used is 0.2 g. For spark OES analysis, the surface of the material needs to be prepared by milling. The minimum area to be analyzed for spark OES and XRF analysis is 30 mm^2.



Traceability
Traceability of the certified mass fractions to the SI (Système International d'Unités) is ensured by calibration using certified standard solutions.

Accreditation
Suisse Technology Partners Ltd. is accredited as a producer of reference materials and certified reference materials according to ISO 17034 (SRMS 0006). This material was produced according to the rules of ISO 17034 and analyzed in our own laboratories accredited according to ISO/IEC 17025 (STS 0023). This material is an accredited certified reference material according to ISO 17034 (SRMS 0006).

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ISO 17034 (SRMS 0006)

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Certificate version 001: 12-Aug-2024
This certificate is valid until: Aug / 2049